



PMDT290UCE

20 / 20 V, 800 / 550 mA N/P-channel Trench MOSFET

Rev. 1 — 6 October 2011

Product data sheet

1. Product profile

1.1 General description

Complementary N/P-channel enhancement mode Field-Effect Transistor (FET) in an ultra small and flat lead SOT666 Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

1.2 Features and benefits

- Very fast switching
- Trench MOSFET technology
- ESD protection up to 2 kV
- AEC-Q101 qualified

1.3 Applications

- Relay driver
- High-speed line driver
- Low-side loadswitch
- Switching circuits

1.4 Quick reference data

Table 1. Quick reference data

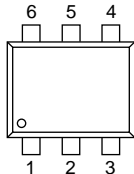
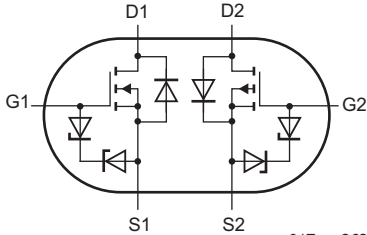
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
TR1 (N-channel), Static characteristics						
R_{DSon}	drain-source on-state resistance	$V_{GS} = 4.5\text{ V}; I_D = 500\text{ mA}; T_j = 25\text{ °C}$	-	290	380	m Ω
TR2 (P-channel), Static characteristics						
R_{DSon}	drain-source on-state resistance	$V_{GS} = -4.5\text{ V}; I_D = -400\text{ mA}; T_j = 25\text{ °C}$	-	0.67	0.85	Ω
TR1 (N-channel)						
V_{DS}	drain-source voltage	$T_j = 25\text{ °C}$	-	-	20	V
V_{GS}	gate-source voltage		-8	-	8	V
I_D	drain current	$V_{GS} = 4.5\text{ V}; T_{amb} = 25\text{ °C}$	[1]	-	800	mA
TR2 (P-channel)						
V_{DS}	drain-source voltage	$T_j = 25\text{ °C}$	-	-	-20	V
V_{GS}	gate-source voltage		-8	-	8	V
I_D	drain current	$V_{GS} = -4.5\text{ V}; T_{amb} = 25\text{ °C}$	[1]	-	-550	mA

[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source TR1	 <p>SOT666</p>	 <p>017aaa262</p>
2	G1	gate TR1		
3	D2	drain TR2		
4	S2	source TR2		
5	G2	gate TR2		
6	D1	drain TR1		

3. Ordering information

Table 3. Ordering information

Type number	Package		Version
	Name	Description	
PMDT290UCE	-	plastic surface-mounted package; 6 leads	SOT666

4. Marking

Table 4. Marking codes

Type number	Marking code
PMDT290UCE	AF

5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

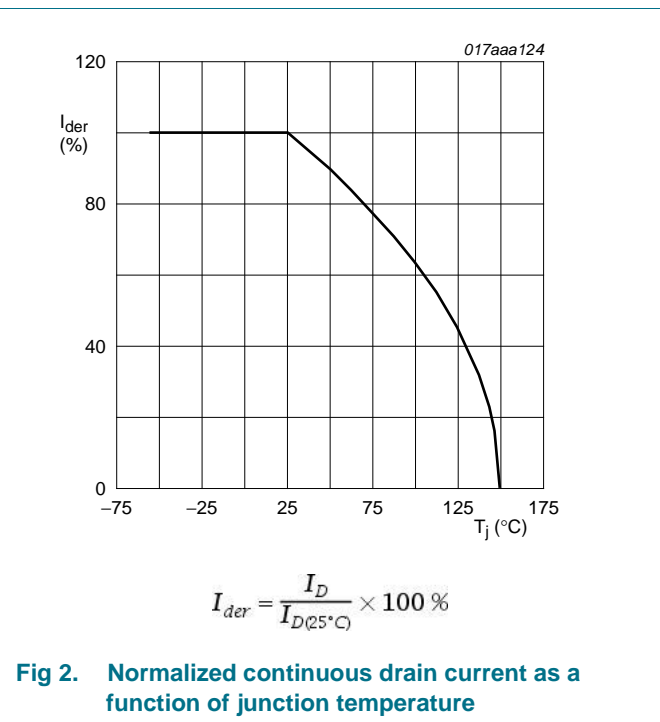
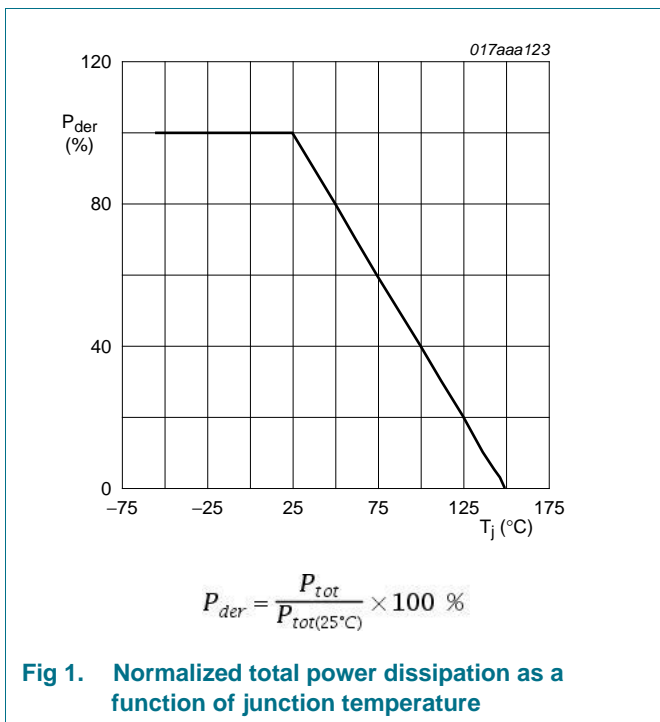
Symbol	Parameter	Conditions	Min	Max	Unit
TR1 (N-channel)					
V_{DS}	drain-source voltage	$T_j = 25\text{ °C}$	-	20	V
V_{GS}	gate-source voltage		-8	8	V
I_D	drain current	$V_{GS} = 4.5\text{ V}; T_{amb} = 25\text{ °C}$	[1]	800	mA
		$V_{GS} = 4.5\text{ V}; T_{amb} = 100\text{ °C}$	[1]	500	mA
I_{DM}	peak drain current	$T_{amb} = 25\text{ °C}; \text{single pulse}; t_p \leq 10\text{ }\mu\text{s}$	-	3.2	A
P_{tot}	total power dissipation	$T_{amb} = 25\text{ °C}$	[2]	330	mW
			[1]	390	mW
		$T_{sp} = 25\text{ °C}$	-	1090	mW
TR1 (N-channel), Source-drain diode					
I_S	source current	$T_{amb} = 25\text{ °C}$	[1]	370	mA
TR1 N-channel), ESD maximum rating					
V_{ESD}	electrostatic discharge voltage	HBM	[3]	2000	V

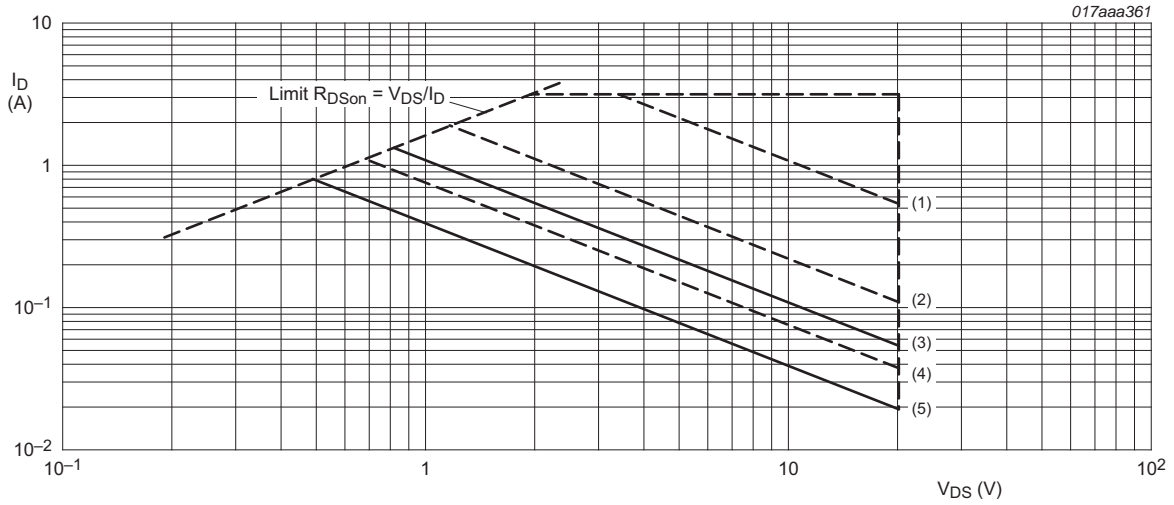
Table 5. Limiting values ...continued

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit	
TR2 (P-channel)						
V _{DS}	drain-source voltage	T _j = 25 °C	-	-20	V	
V _{GS}	gate-source voltage		-8	8	V	
I _D	drain current	V _{GS} = -4.5 V; T _{amb} = 25 °C	[1]	-	-550	mA
		V _{GS} = -4.5 V; T _{amb} = 100 °C	[1]	-	-350	mA
I _{DM}	peak drain current	T _{amb} = 25 °C; single pulse; t _p ≤ 10 μs	-	-2.2	A	
P _{tot}	total power dissipation	T _{amb} = 25 °C	[2]	-	330	mW
			[1]	-	390	mW
		T _{sp} = 25 °C		-	1090	mW
TR2 (P-channel), Source-drain diode						
I _S	source current	T _{amb} = 25 °C	[1]	-	-370	mA
TR2 (P-channel), ESD maximum rating						
V _{ESD}	electrostatic discharge voltage	HBM	[3]	-	2000	V
Per device						
P _{tot}	total power dissipation	T _{amb} = 25 °C	[2]	-	500	mW
T _j	junction temperature			-55	150	°C
T _{amb}	ambient temperature			-55	150	°C
T _{stg}	storage temperature			-65	150	°C

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².
- [2] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper; tin-plated and standard footprint.
- [3] Measured between all pins.





I_{DM} = single pulse

(1) $t_p = 1$ ms

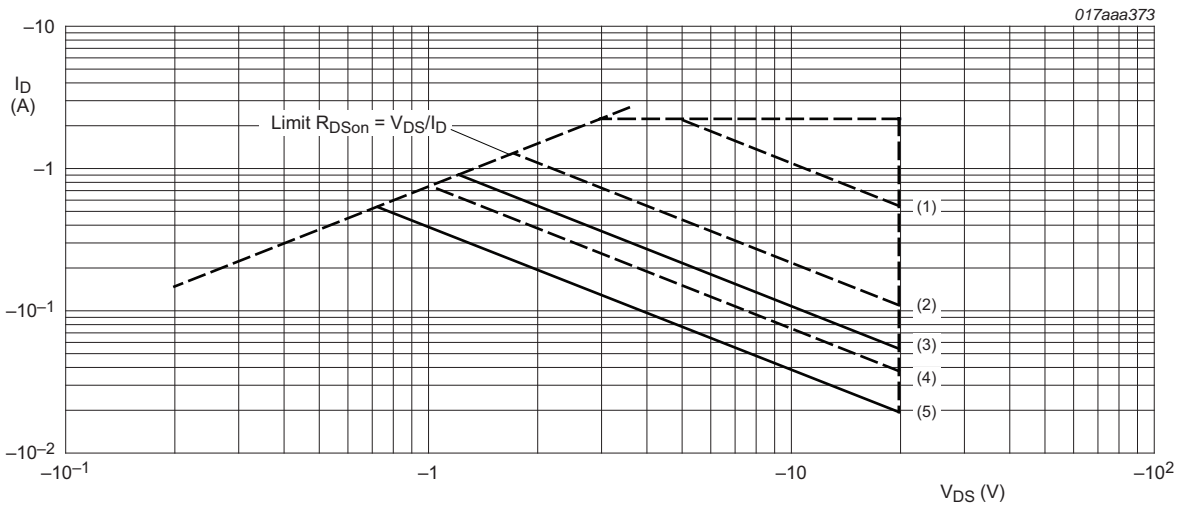
(2) $t_p = 10$ ms

(3) DC; $T_{sp} = 25$ °C

(4) $t_p = 100$ ms

(5) DC; $T_{amb} = 25$ °C; drain mounting pad 1 cm^2

Fig 3. Safe operating area TR1 (N-channel); junction to ambient; continuous and peak drain currents as a function of drain-source voltage



I_{DM} = single pulse

(1) $t_p = 1$ ms

(2) $t_p = 10$ ms

(3) DC; $T_{sp} = 25$ °C

(4) $t_p = 100$ ms

(5) DC; $T_{amb} = 25$ °C; drain mounting pad 1 cm^2

Fig 4. Safe operating area TR2 (P-channel); junction to ambient; continuous and peak drain currents as a function of drain-source voltage

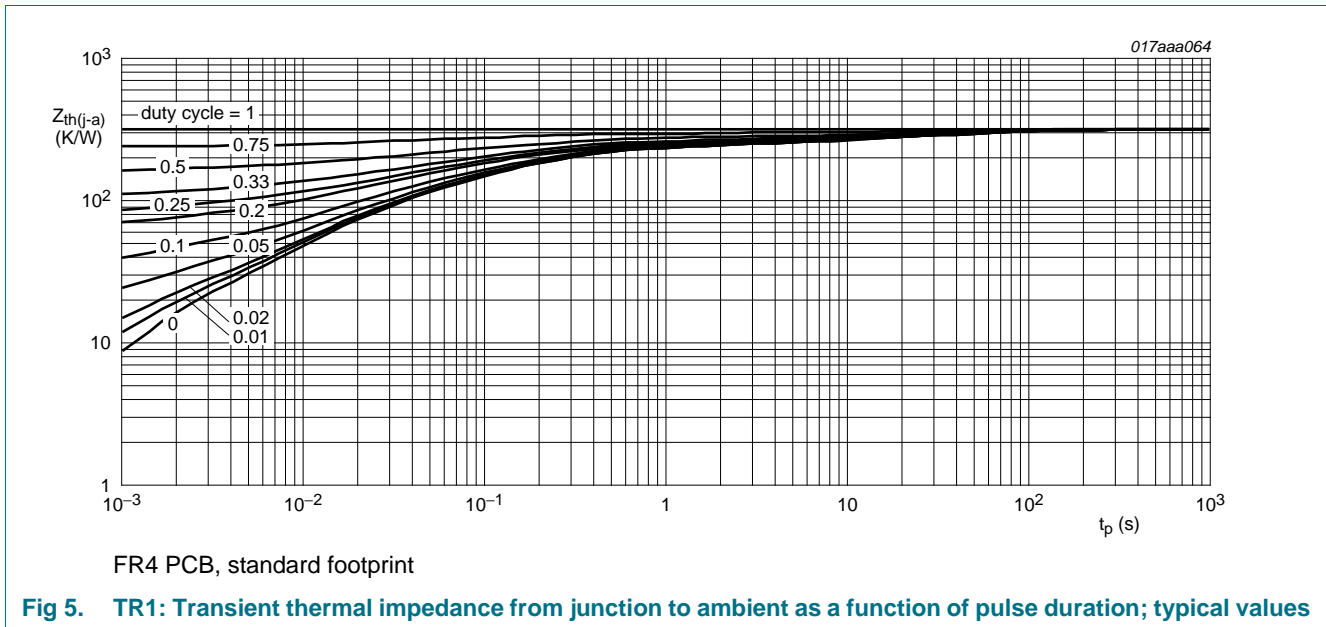
6. Thermal characteristics

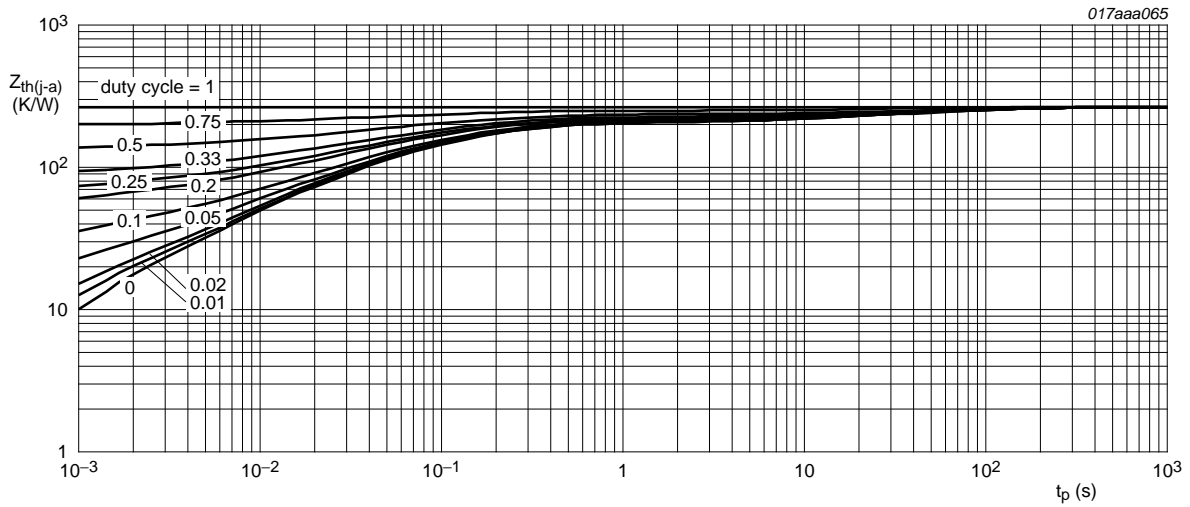
Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
TR1 (N-channel)							
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	[1]	-	330	380	K/W
			[2]	-	280	320	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	115	K/W	
TR2 (P-channel)							
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	[1]	-	330	380	K/W
			[2]	-	280	320	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	115	K/W	
Per device							
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	[1]	-	-	250	K/W

[1] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper; tin-plated and standard footprint.

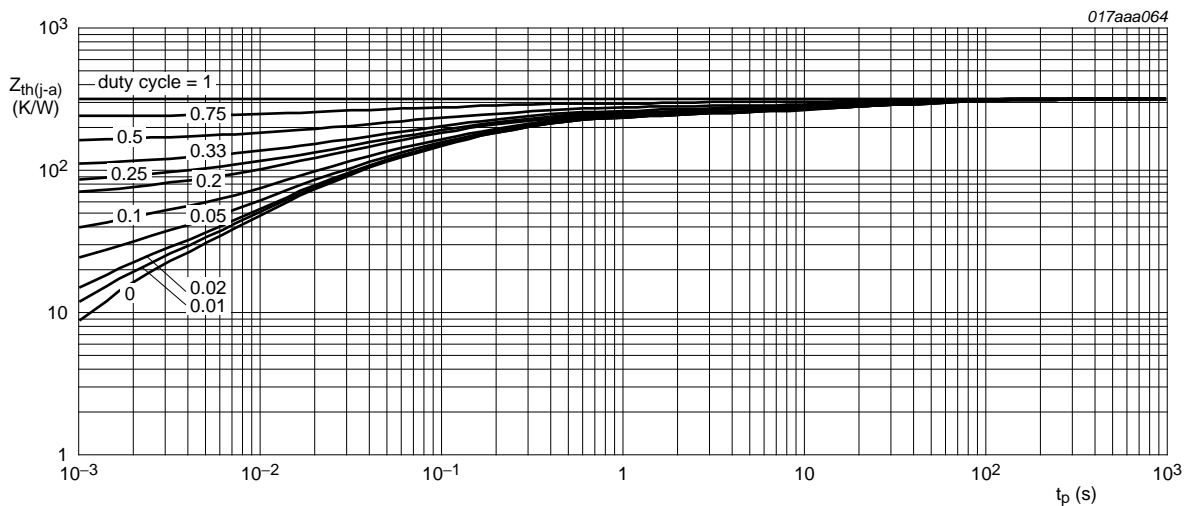
[2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².





FR4 PCB, mounting pad for drain 1 cm²

Fig 6. TR1: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, standard footprint

Fig 7. TR2: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

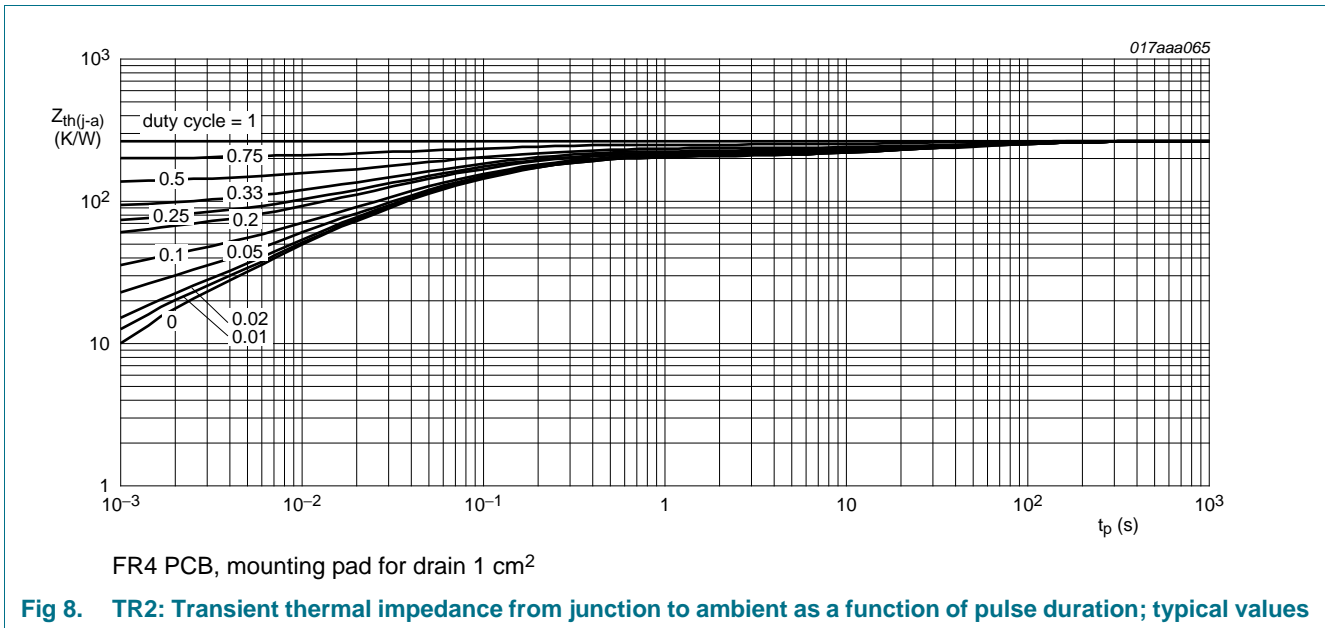


Fig 8. TR2: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

7. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
TR1 (N-channel), Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	20	-	-	V
V_{GSth}	gate-source threshold voltage	$I_D = 250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ }^\circ C$	0.5	0.75	0.95	V
I_{DSS}	drain leakage current	$V_{DS} = 20 V; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	1	μA
		$V_{DS} = 20 V; V_{GS} = 0 V; T_j = 150 \text{ }^\circ C$	-	-	10	μA
I_{GSS}	gate leakage current	$V_{GS} = 8 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	2	μA
		$V_{GS} = -8 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	2	μA
		$V_{GS} = 4.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	500	nA
		$V_{GS} = -4.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	500	nA
		$V_{GS} = 4.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	500	nA
R_{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 V; I_D = 500 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	290	380	m Ω
		$V_{GS} = 4.5 V; I_D = 500 \text{ mA}; T_j = 150 \text{ }^\circ C$	-	460	610	m Ω
		$V_{GS} = 2.5 V; I_D = 200 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	420	620	m Ω
		$V_{GS} = 1.8 V; I_D = 10 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	0.6	1.1	Ω
g_{fs}	transfer conductance	$V_{DS} = 10 V; I_D = 200 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	1.6	-	S
TR1 (N-channel), Dynamic characteristics						
$Q_{G(tot)}$	total gate charge	$V_{DS} = 10 V; I_D = 500 \text{ mA}; V_{GS} = 4.5 V; T_j = 25 \text{ }^\circ C$	-	0.45	0.68	nC
Q_{GS}	gate-source charge	$T_j = 25 \text{ }^\circ C$	-	0.15	-	nC
Q_{GD}	gate-drain charge		-	0.15	-	nC

Table 7. Characteristics ...continued

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
C _{iss}	input capacitance	V _{DS} = 10 V; f = 1 MHz; V _{GS} = 0 V; T _j = 25 °C	-	55	83	pF
C _{oss}	output capacitance		-	15	-	pF
C _{rss}	reverse transfer capacitance		-	7	-	pF
t _{d(on)}	turn-on delay time	V _{DS} = 10 V; R _L = 250 Ω; V _{GS} = 4.5 V; R _{G(ext)} = 6 Ω; T _j = 25 °C	-	6	12	ns
t _r	rise time		-	4	-	ns
t _{d(off)}	turn-off delay time		-	86	172	ns
t _f	fall time		-	31	-	ns
TR1 (N-channel), Source-drain diode characteristics						
V _{SD}	source-drain voltage	I _S = 300 mA; V _{GS} = 0 V; T _j = 25 °C	0.48	0.77	1.2	V
TR2 (P-channel), Static characteristics						
V _{(BR)DSS}	drain-source breakdown voltage	I _D = -250 μA; V _{GS} = 0 V; T _j = 25 °C	-20	-	-	V
V _{GSth}	gate-source threshold voltage	I _D = -250 μA; V _{DS} = V _{GS} ; T _j = 25 °C	-0.5	-0.8	-1.3	V
I _{DSS}	drain leakage current	V _{DS} = -20 V; V _{GS} = 0 V; T _j = 25 °C	-	-	-1	μA
		V _{DS} = -20 V; V _{GS} = 0 V; T _j = 150 °C	-	-	-10	μA
I _{GSS}	gate leakage current	V _{GS} = 8 V; V _{DS} = 0 V; T _j = 25 °C	-	-	-2	μA
		V _{GS} = -8 V; V _{DS} = 0 V; T _j = 25 °C	-	-	-2	μA
		V _{GS} = 4.5 V; V _{DS} = 0 V; T _j = 25 °C	-	-	-0.5	μA
		V _{GS} = -4.5 V; V _{DS} = 0 V; T _j = 25 °C	-	-	-0.5	μA
R _{DSon}	drain-source on-state resistance	V _{GS} = -4.5 V; I _D = -400 mA; T _j = 25 °C	-	0.67	0.85	Ω
		V _{GS} = -4.5 V; I _D = -400 mA; T _j = 150 °C	-	1.1	1.4	Ω
		V _{GS} = -2.5 V; I _D = -200 mA; T _j = 25 °C	-	1.2	1.5	Ω
		V _{GS} = -1.8 V; I _D = -10 mA; T _j = 25 °C	-	1.8	2.8	Ω
g _{fs}	transfer conductance	V _{DS} = -10 V; I _D = -200 mA; T _j = 25 °C	-	610	-	mS
TR2 (P-channel), Dynamic characteristics						
Q _{G(tot)}	total gate charge	V _{DS} = -10 V; I _D = -400 mA; V _{GS} = -4.5 V; T _j = 25 °C	-	0.76	1.14	nC
Q _{GS}	gate-source charge		-	0.28	-	nC
Q _{GD}	gate-drain charge		-	0.18	-	nC
C _{iss}	input capacitance	V _{DS} = -10 V; f = 1 MHz; V _{GS} = 0 V; T _j = 25 °C	-	58	87	pF
C _{oss}	output capacitance		-	21	-	pF
C _{rss}	reverse transfer capacitance		-	12	-	pF
t _{d(on)}	turn-on delay time	V _{DS} = -10 V; R _L = 250 Ω; V _{GS} = -4.5 V; R _{G(ext)} = 6 Ω; T _j = 25 °C	-	18	36	ns
t _r	rise time		-	30	-	ns
t _{d(off)}	turn-off delay time		-	80	160	ns
t _f	fall time		-	72	-	ns
TR2 (P-channel), Source-drain diode characteristics						
V _{SD}	source-drain voltage	I _S = -300 mA; V _{GS} = 0 V; T _j = 25 °C	-0.48	-0.84	-1.2	V

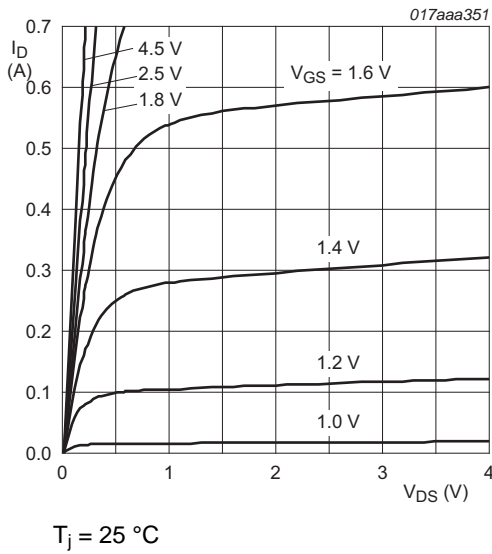


Fig 9. TR1; Output characteristics: drain current as a function of drain-source voltage; typical values

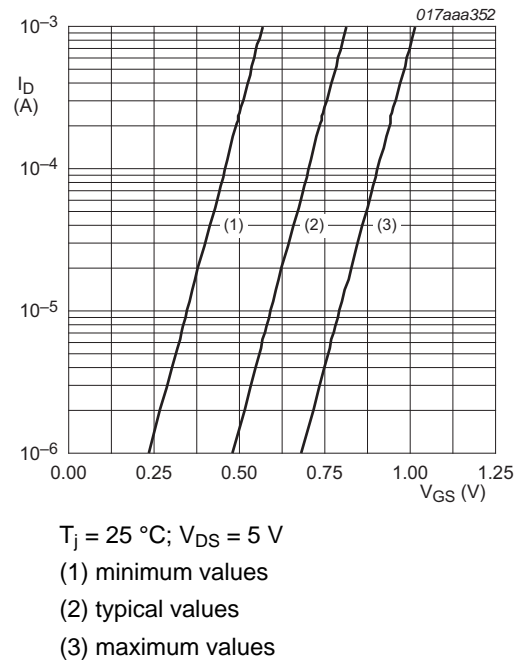
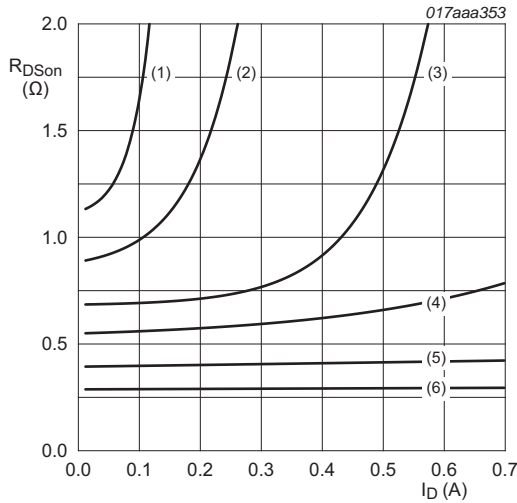
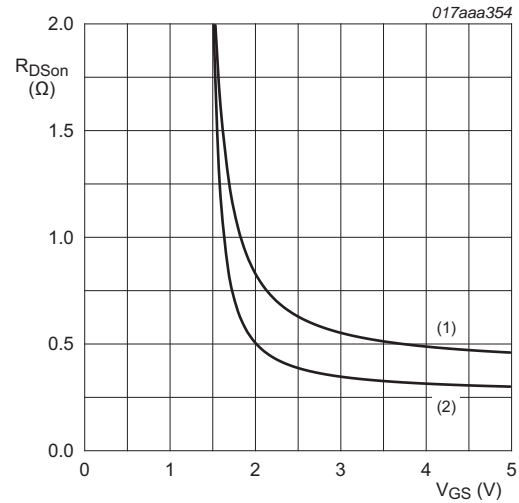


Fig 10. TR1; Sub-threshold drain current as a function of gate-source voltage



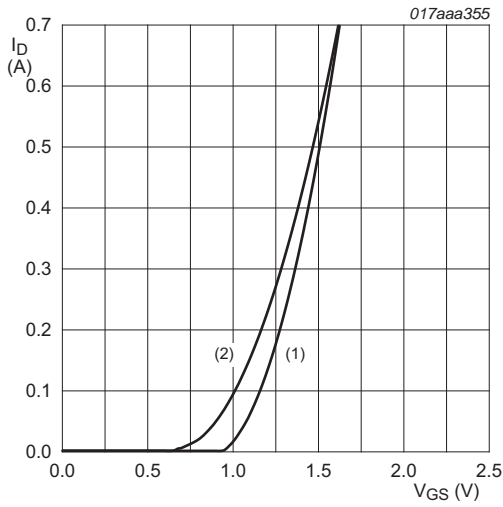
$T_j = 25^\circ\text{C}$
 (1) $V_{GS} = 1.3\text{ V}$
 (2) $V_{GS} = 1.4\text{ V}$
 (3) $V_{GS} = 1.6\text{ V}$
 (4) $V_{GS} = 1.8\text{ V}$
 (5) $V_{GS} = 2.5\text{ V}$
 (6) $V_{GS} = 4.5\text{ V}$

Fig 11. TR1; Drain-source on-state resistance as a function of drain current; typical values



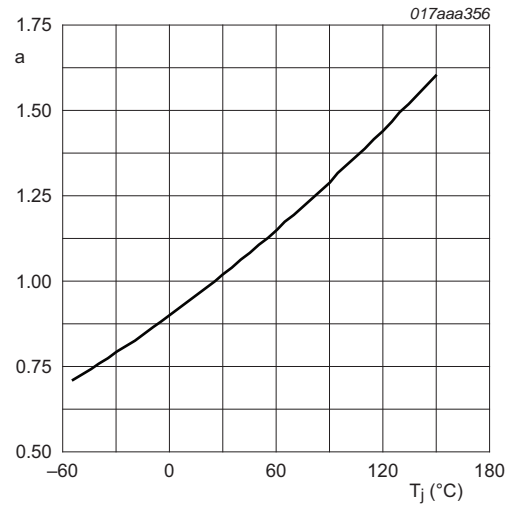
$I_D = 400\text{ mA}$
 (1) $T_j = 150^\circ\text{C}$
 (2) $T_j = 25^\circ\text{C}$

Fig 12. TR1; Drain-source on-state resistance as a function of gate-source voltage; typical values



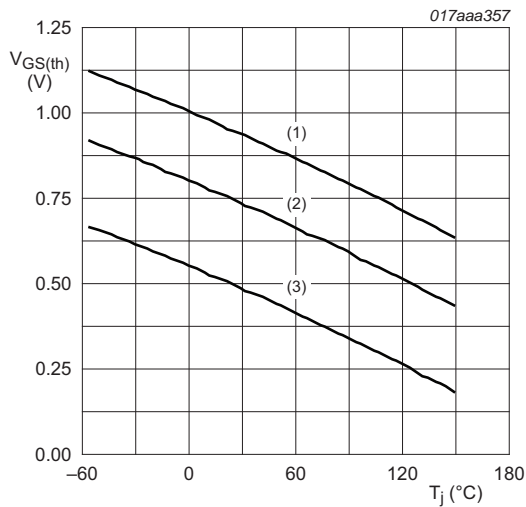
$V_{DS} > I_D \times R_{DSon}$
 (1) $T_j = 25\text{ °C}$
 (2) $T_j = 150\text{ °C}$

Fig 13. TR1; Transfer characteristics: drain current as a function of gate-source voltage; typical values



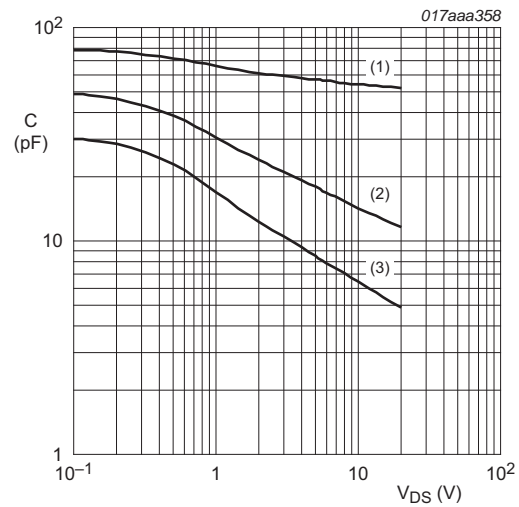
$$a = \frac{R_{DSon}}{R_{DSon(25^\circ C)}}$$

Fig 14. TR1; Normalized drain-source on-state resistance as a function of junction temperature; typical values



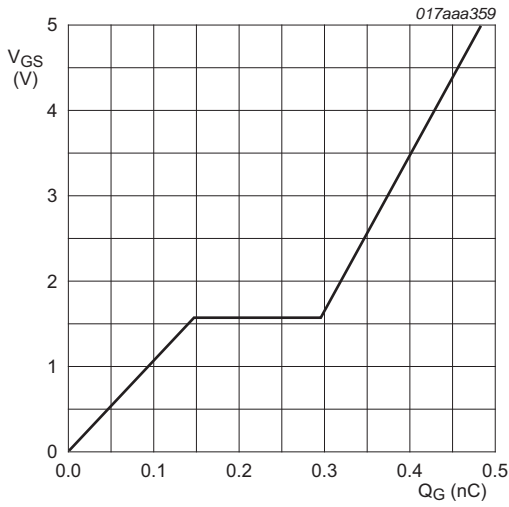
$I_D = 0.25\text{ mA}; V_{DS} = V_{GS}$
 (1) maximum values
 (2) typical values
 (3) minimum values

Fig 15. TR1; Gate-source threshold voltage as a function of junction temperature



$f = 1\text{ MHz}; V_{GS} = 0\text{ V}$
 (1) C_{iss}
 (2) C_{oss}
 (3) C_{rss}

Fig 16. TR1; Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



$I_D = 0.5 \text{ A}; V_{DS} = 10 \text{ V}; T_{amb} = 25 \text{ }^\circ\text{C}$

Fig 17. TR1; Gate-source voltage as a function of gate charge; typical values

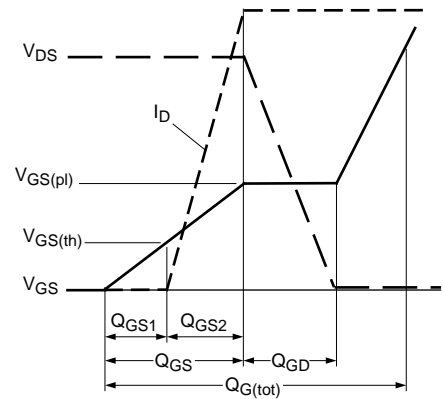
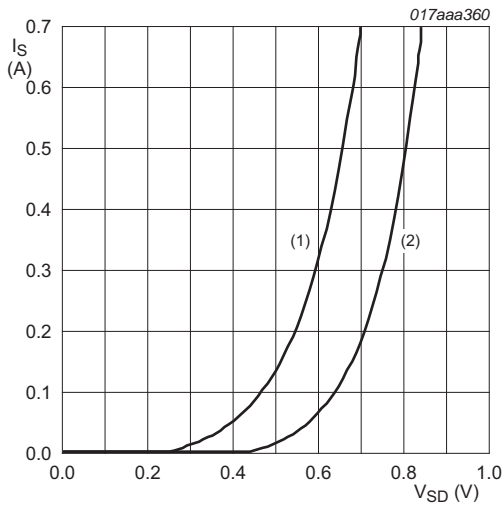
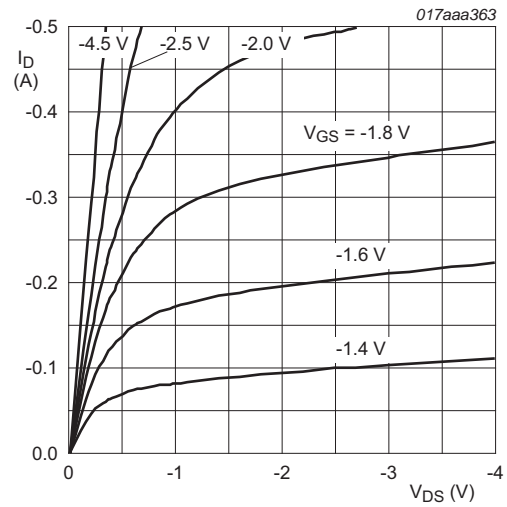


Fig 18. Gate charge waveform definitions



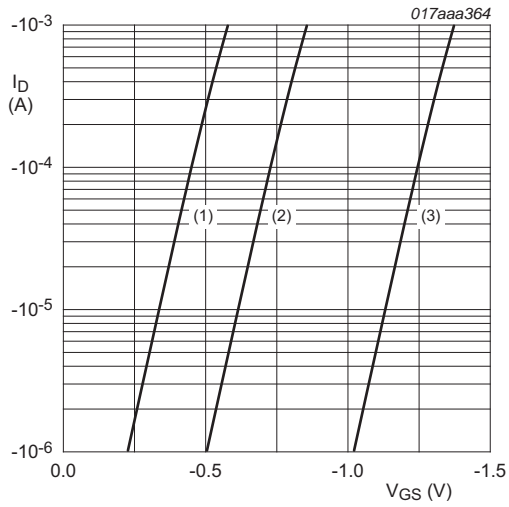
$V_{GS} = 0 \text{ V}$
 (1) $T_j = 150 \text{ }^\circ\text{C}$
 (2) $T_j = 25 \text{ }^\circ\text{C}$

Fig 19. TR1; Source current as a function of source-drain voltage; typical values



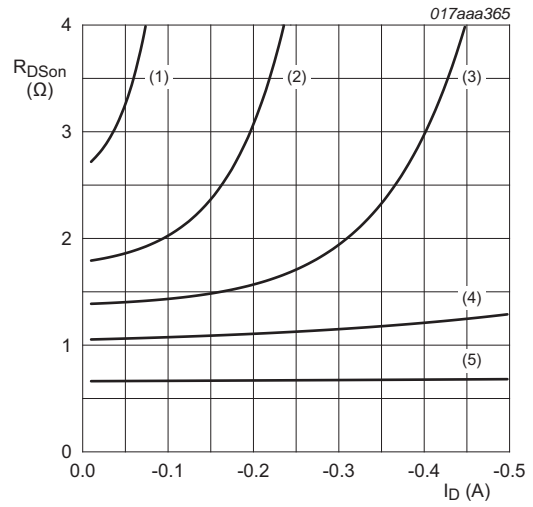
$T_j = 25 \text{ }^\circ\text{C}$

Fig 20. TR2; Output characteristics: drain current as a function of drain-source voltage; typical values



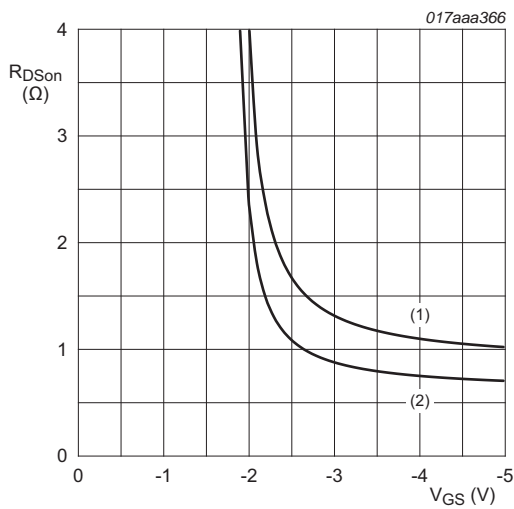
$T_j = 25\text{ }^\circ\text{C}; V_{DS} = -5\text{ V}$
 (1) minimum values
 (2) typical values
 (3) maximum values

Fig 21. TR2; Sub-threshold drain current as a function of gate-source voltage



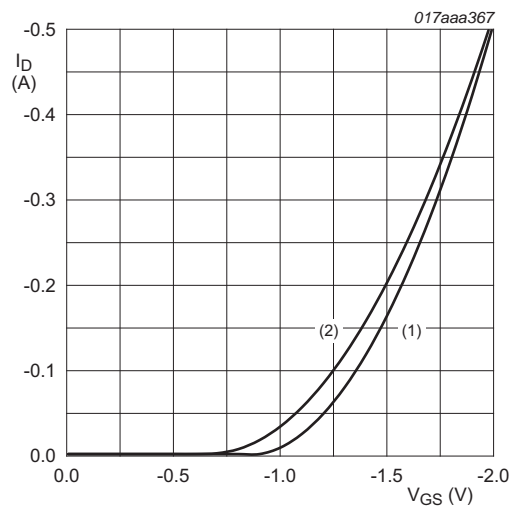
$T_j = 25\text{ }^\circ\text{C}$
 (1) $V_{GS} = -1.5\text{ V}$
 (2) $V_{GS} = -1.8\text{ V}$
 (3) $V_{GS} = -2.0\text{ V}$
 (4) $V_{GS} = -2.5\text{ V}$
 (5) $V_{GS} = -4.5\text{ V}$

Fig 22. TR2; Drain-source on-state resistance as a function of drain current; typical values



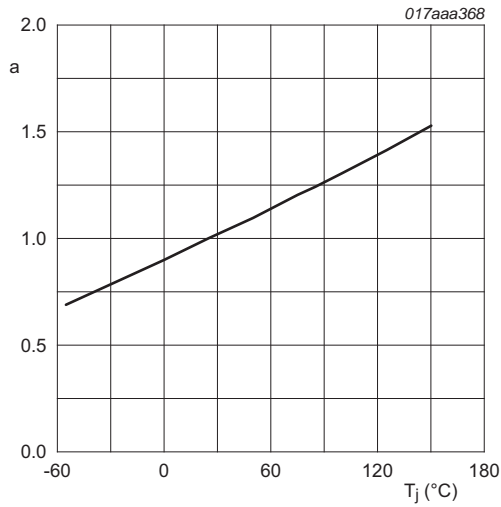
$I_D = -400\text{ mA}$
 (1) $T_j = 150\text{ }^\circ\text{C}$
 (2) $T_j = 25\text{ }^\circ\text{C}$

Fig 23. TR2; Drain-source on-state resistance as a function of gate-source voltage; typical values



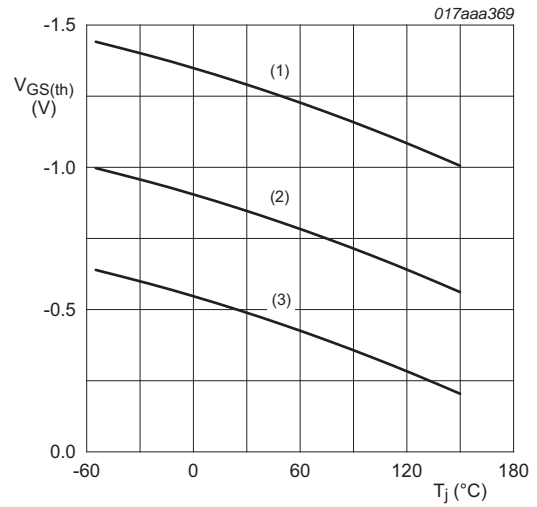
$V_{DS} > I_D \times R_{DSon}$
 (1) $T_j = 25\text{ }^\circ\text{C}$
 (2) $T_j = 150\text{ }^\circ\text{C}$

Fig 24. TR2; Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$a = \frac{R_{DS(on)}}{R_{DS(on)(25^\circ C)}}$$

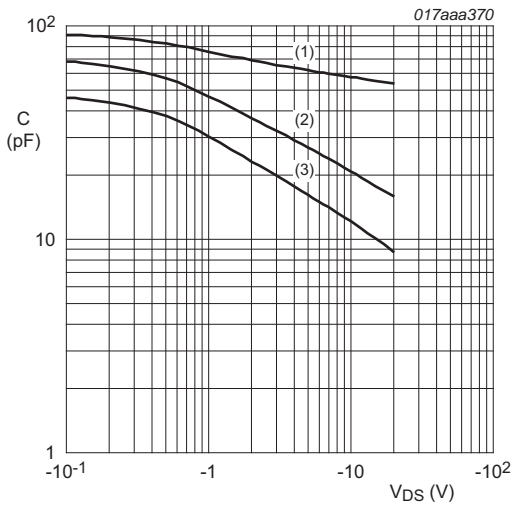
Fig 25. TR2; Normalized drain-source on-state resistance as a function of ambient temperature; typical values



$I_D = -0.25 \text{ mA}; V_{DS} = V_{GS}$

- (1) maximum values
- (2) typical values
- (3) minimum values

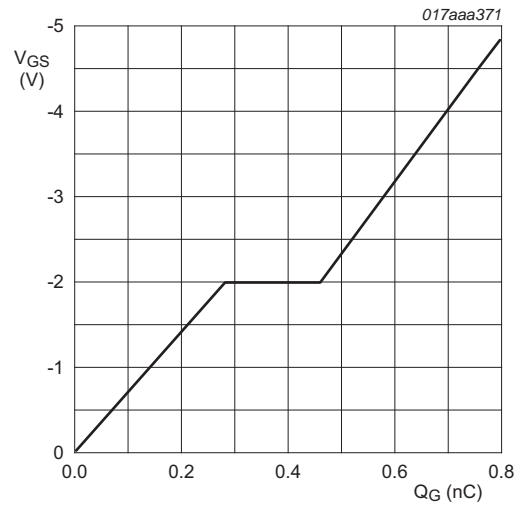
Fig 26. TR2; Gate-source threshold voltage as a function of junction temperature



$f = 1 \text{ MHz}; V_{GS} = 0 \text{ V}$

- (1) C_{iss}
- (2) C_{oss}
- (3) C_{rss}

Fig 27. TR2; Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



$I_D = -0.4 \text{ A}; V_{DD} = -10 \text{ V}; T_{amb} = 25 \text{ }^\circ\text{C}$

Fig 28. TR2; Gate-source voltage as a function of gate charge; typical values

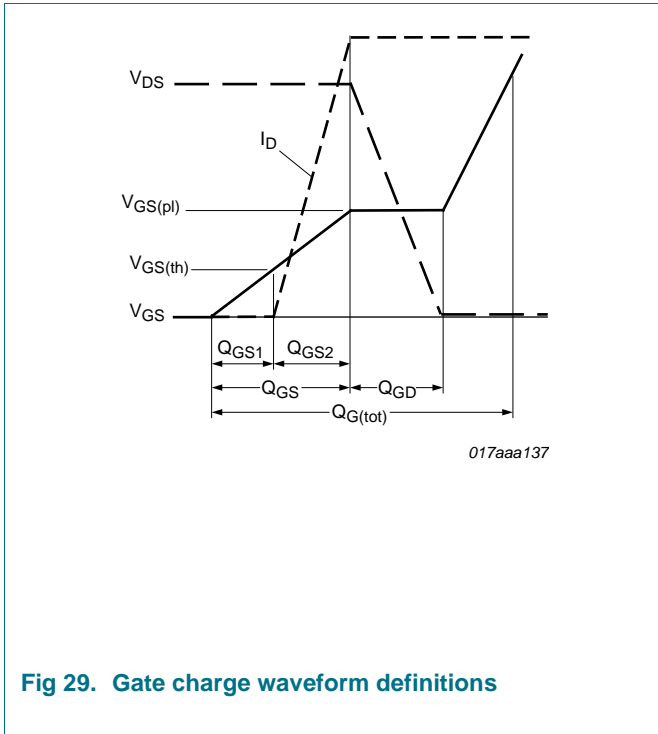


Fig 29. Gate charge waveform definitions

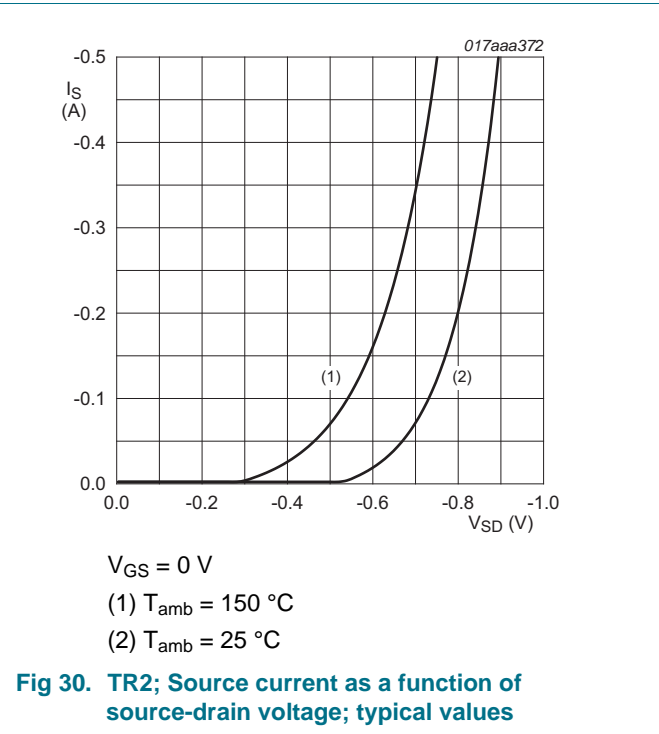


Fig 30. TR2; Source current as a function of source-drain voltage; typical values

8. Test information

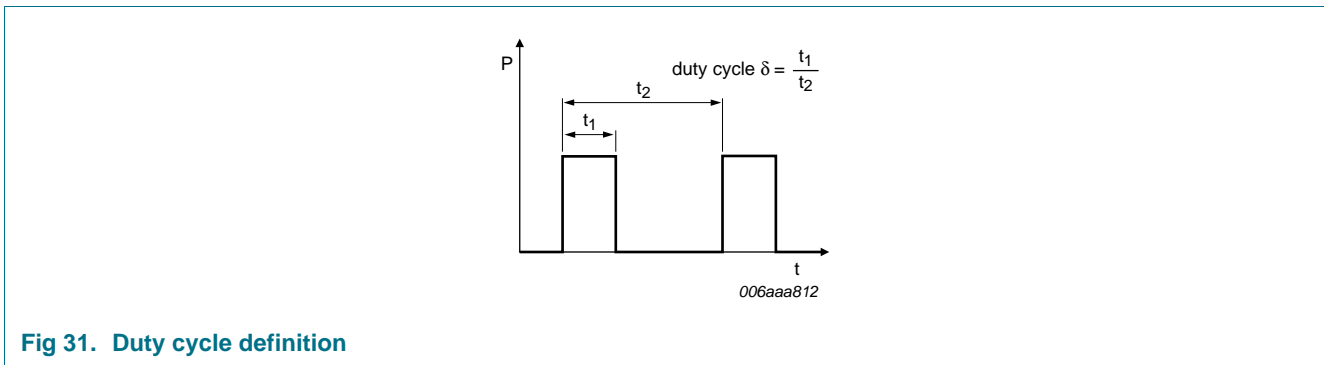


Fig 31. Duty cycle definition

8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard Q101 - Stress test qualification for discrete semiconductors, and is suitable for use in automotive applications.

9. Package outline

Plastic surface-mounted package; 6 leads

SOT666

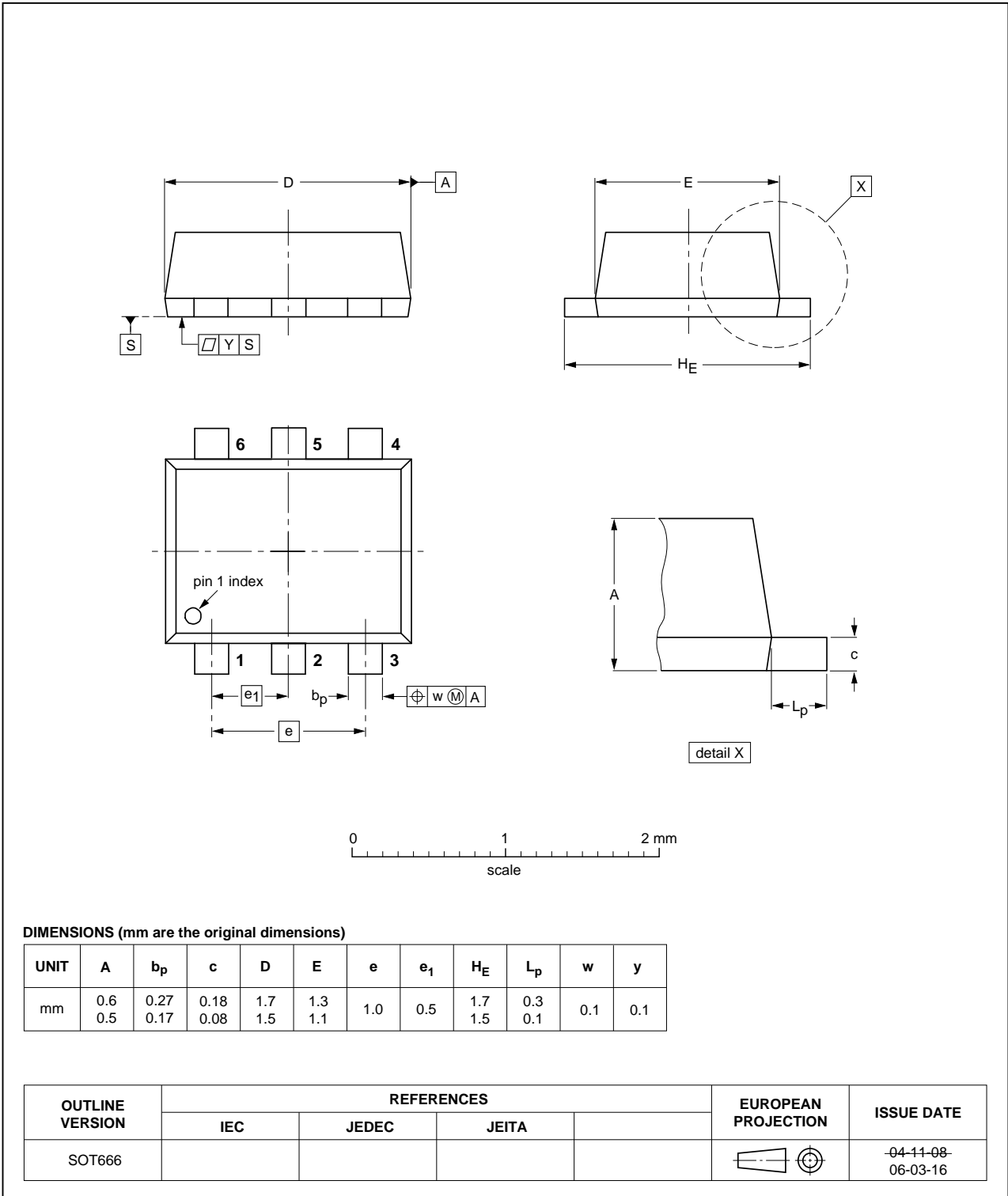


Fig 32. Package outline SOT666

10. Soldering

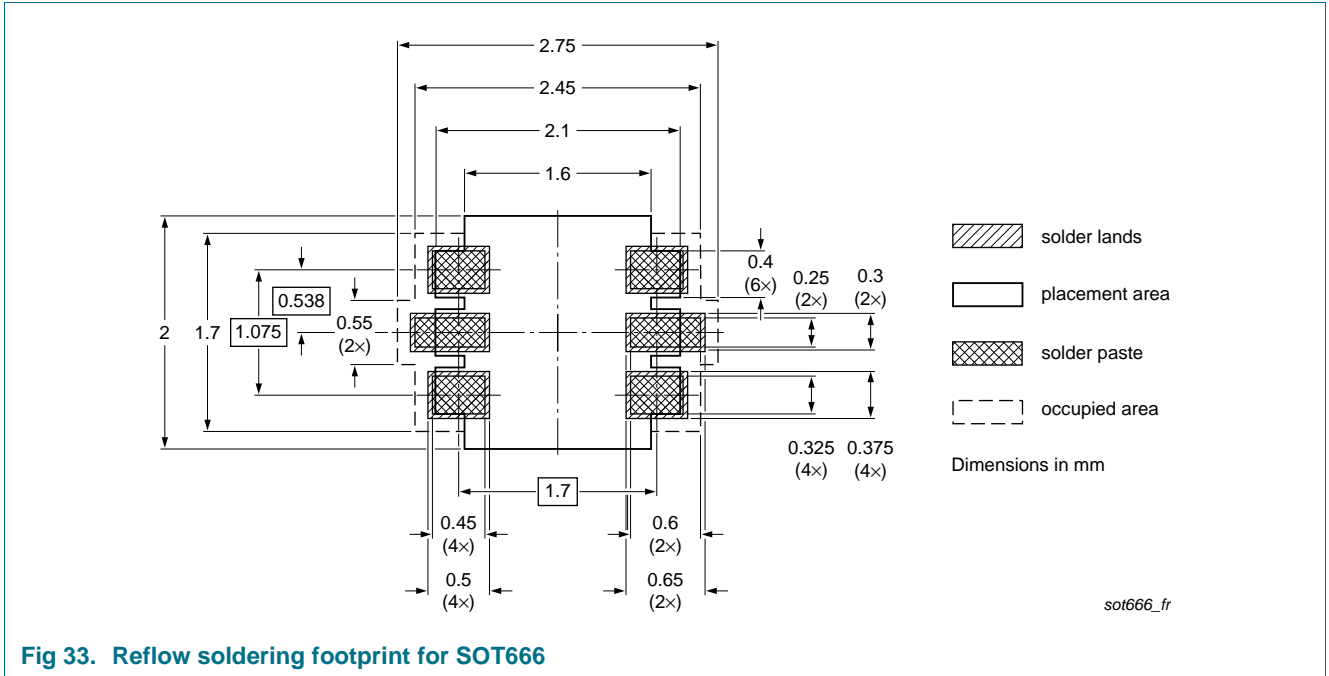


Fig 33. Reflow soldering footprint for SOT666

11. Revision history

Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PMDT290UCE v.1	20111006	Product data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status ^[1] ^[2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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